

**Amendments to the Specification:**

Please replace the paragraph beginning on page 5, paragraph [0014], line 10, with the following paragraph as amended.

[0014] FIG. 5 illustrates a top view of the constraining layer according to an embodiment of the invention, wherein L is a shortest length of the constraining layer; c is a ~~radius~~diameter of a circumscribed circle of each window; a is a distance between the adjacent circumscribed circles; and b is a distance between the most outside window and an edge of the constraining layer.

Please replace the paragraph beginning on page 10, paragraph [0031], line 18, with the following paragraph as amended.

[0031] In a preferred embodiment of the invention, a constraining layer with the shortest length L is punched to form at least one window thereon (referring to FIG. 5). The window can be in any shape in a circumscribed circle with the ~~radius~~diameter c, the distance between the adjacent circumscribed circles is a, and the distance between the outermost window and the edge of the constraining layer is b; wherein  $c < 0.5L$ ,  $a > 0.1c$ ,  $b > 0.1c$ . According to the invention, ~~radiuses~~diameters of each circumscribed circle can be different, provided that the windows in positions for exposing the heterogeneous material pattern are disposed on the dielectric layer.

Please replace the paragraph beginning on page 20, paragraph [0069], line 17, with the following paragraph as amended.

[0069] The X-Y dimension shrinkage rates of the monolithic structure under different values of  $[[m]]_n$  were measured and listed in Table 2:

Table 2

$[[m]]_n$	X-Y shrinkage rate (%)
0	1.84
1	1.77
2	1.69